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| Notice of References Cited | Application/Control No. 10/529,160 | Applicant(s)/Patent Under Reexamination KANAYAMA ET AL. | |
| | Examiner Jason Recek | Art Unit 2142 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-2003/0088471 A1 | 05-2003 | Tanigaki et al. | 705/20 |
| * | B | US-2003/0110443 A1 | 06-2003 | Yankovich et al. | 715/501.1 |
| * | C | US-7,111,019 B1 | 09-2006 | Nishizawa et al. | 707/201 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
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FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
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